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Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		RULE 33(b) DIVISION OF APPLICATION NO. 10267,834	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANT(S) Takuroh OZAWA et al.			
				FILING DATE July 24, 2003		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
J.L.		5,714,838	2-1998	HAIGHT et al.			
		5,072,450	6-2000	YAMADA et al.			
		5,587,329	12-96	HSEUH et al.			
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J.L.		EP-A1-0 653 741	05-95	Europe			
		JP-A-8-129358	05-96	Japan			
		JP B-227276	09-96	Japan			
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J.L.		Alan G. Lewis, et al., Physical Mechanisms For Short Channel Effects In Polysilicon Thin Film Transistors, IEEE, 1989, pgs. 13A.1-13A.4					
J.L.		Alan G. Lewis et al., Polysilicon TFT Circuit Design and Performance, IEEE Journal of Solid-State Circuits, December 1992, Vol. 27, No. 12, pgs. 1833-1842.					
EXAMINER <i>Jean degenance</i>				DATE CONSIDERED 6-9-05			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: July 24, 2003